SCLS019B - MARCH 1984 - REVISED MAY 1997

- Inputs Are TTL-Voltage Compatible
- True Logic
- High-Current 3-State Outputs Can Drive up to 15 LSTTL Loads
- Package Options Include Plastic Small-Outline (DW) and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

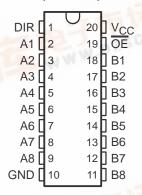
These octal bus transceivers are designed for asynchronous two-way communication between data buses. These devices transmit data from the A bus to the B bus or from the B bus to the A bus, depending upon the level at the direction-control (DIR) input. The output-enable (\overline{OE}) input can be used to disable the device so the buses are effectively isolated.

The SN54HCT645 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HCT645 is characterized for operation from –40°C to 85°C.

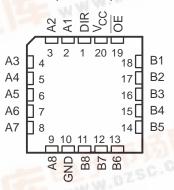
FUNCTION TABLE

INP	UTS	ODEDATION			
OE	DIR	OPERATION			
L	L	B data to A bus			
L	Н	A data to B bus			
Н	X	Isolation			
	- 1	9-7-1-66			

SN54HCT645 . . . J OR W PACKAGE SN74HCT645 . . . DW OR N PACKAGE (TOP VIEW)



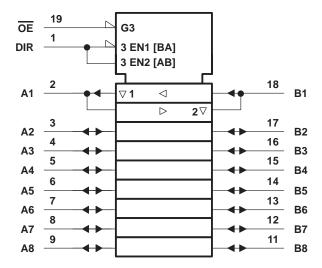
SN54HCT645 . . . FK PACKAGE (TOP VIEW)



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

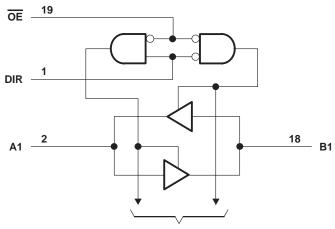


logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Transceivers

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absolute maximum ratings over operating free-air temperature range[†]

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) (see Note 1)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC}) (see Note 1)	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±35 mA
Continuous current through V _{CC} or GND	±70 mA
Package thermal impedance, θ_{JA} (see Note 2): DW package	97°C/W
N package	67°C/W
Storage temperature range, T _{sto}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

					SN54HCT645			SN74HCT645		
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		4.5	5	\$ 5.5	4.5	5	5.5	V	
VIH	High-level input voltage	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	2	Š	1/5	2			V	
VIL	Low-level input voltage	V _{CC} = 4.5 V to 5.5 V	0	PA	0.8	0		0.8	V	
٧ı	Input voltage		0	1	VCC	0		VCC	V	
٧o	Output voltage		0	2	VCC	0		VCC	V	
t _t	Input transition (rise and fall) time		Q ^C	7	500	0		500	ns	
TA	Operating free-air temperature		-55		125	-40		85	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DAD	AMETER	TEST CONDITIONS		V	T _A = 25°C			SN54HCT645		SN74HCT645		UNIT
FAR	PARAMETER TEST CONDITIONS		vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
VOH		VI = VIH or VIL	I _{OH} = -20 μA	4.5 V	4.4	4.499		4.4		4.4		V
VOH		AI = AIH OL AIL	$I_{OH} = -6 \text{ mA}$	4.5 V	3.98	4.3		3.7		3.84		V
V/01		Ιομ = 20 μΑ		4.5 V		0.001	0.1		0.1		0.1	V
VOL		$V_I = V_{IH}$ or V_{IL}	$I_{OL} = 6 \text{ mA}$	4.5 V		0.17	0.26		0.4		0.33	V
Ц	DIR or OE	$V_I = V_{CC}$ or 0		5.5 V		±0.1	±100		±1000		±1000	nA
loz	A or B	VO = VCC or 0		5.5 V		±0.01	±0.5	4	±10		±5	μΑ
Icc		$V_I = V_{CC}$ or 0,	IO = 0	5.5 V			8	2	160		80	μΑ
Δl _{CC} ‡	:	One input at 0.5 V o Other inputs at 0 or	*	5.5 V		1.4	2.4	OKO	3		2.9	mA
Ci	DIR or OE			4.5 V to 5.5 V		3	10		10		10	pF

[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.



^{2.} The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

SN54HCT645, SN74HCT645 OCTAL BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

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switching characteristics over recommended operating free-air temperature range, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то		T,	\ = 25°C	;	SN54HCT645	SN74HCT645	UNIT		
PARAMETER	(INPUT)	(OUTPUT) VC	VCC	MIN	TYP	MAX	MIN MAX	MIN MAX	UNIT		
	A or B	B or A	4.5 V		16	22	33	28			
^t pd	AOIB		5.5 V		14	20	30	25	ns		
	t _{en} $\overline{\text{OE}}$	A or B	4.5 V		25	46	69	58	ns		
^t en			5.5 V		22	41	62	52			
+	^t dis $\overline{\sf OE}$	ŌĒ	0-	OE A or B	4.5 V		26	40	<i>(</i>) 60	50	nc
^t dis			AOIB		AOIB	5.5 V		23	36	54	45
.		I A or B ⊢	4.5 V		9	12	18	15	ns		
t _t			5.5 V		8	11	16	14	115		

switching characteristics over recommended operating free-air temperature range, C_L = 150 pF (unless otherwise noted) (see Figure 1)

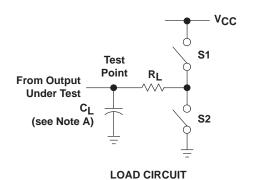
PARAMETER	FROM	FROM TO		T _A = 25°C		SN54HCT645		SN74HCT645		UNIT	
PARAMETER	(INPUT)	(OUTPUT)	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
	A or P	A or B B or A	4.5 V		20	30		45		38	20
^t pd	AOIB		BOIA	5.5 V		18	27	· ·	41		34
	ŌĒ	OE A or B	4.5 V		36	59	00°	89		74	20
^t en			5.5 V		30	53	6,66	80		67	ns
4		A or B	4.5 V		17	42		63		53	
t _t			5.5 V		14	38		57		48	ns

operating characteristics, $T_A = 25^{\circ}C$

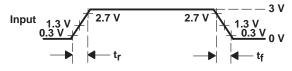
	PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per transceiver	No load	40	pF



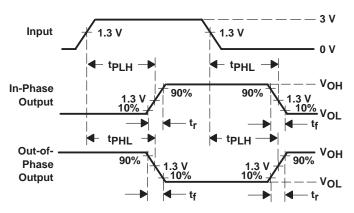
PARAMETER MEASUREMENT INFORMATION

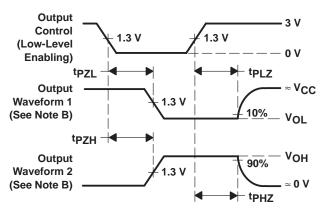


PARAI	/IETER	RL	CL	S1	S2	
	^t PZH	1 k Ω	50 pF	Open	Closed	
^t en	tPZL			Closed	Open	
.	tPHZ	1 k Ω	50 pF	Open	Closed	
^t dis	tPLZ	1 K22	30 pr	Closed	Open	
t _{pd} or	t _t	_	50 pF or 150 pF	Open	Open	



VOLTAGE WAVEFORM INPUT RISE AND FALL TIMES





VOLTAGE WAVEFORMS PROPAGATION DELAY AND OUTPUT RISE AND FALL TIMES

VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES FOR 3-STATE OUTPUTS

NOTES: A. C_L includes probe and test-fixture capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 6 ns.
- D. The outputs are measured one at a time with one input transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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